


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>09886663</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>SARANGAPANI ET AL.</p>
	<p>Examiner</p> <p>PAK, JOHN</p>	<p>Art Unit</p> <p>1616</p>

SEARCHED			
Class	Subclass	Date	Examiner
424	404, 443, 486, 618, 619	7/08	JP
514	184, 495, 974	7/08	JP

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor names searched	6/07	JP
EAST, see printout.	6/07	JP
Inventor names searched	7/08	JP
EAST, Files USPAT and DERWENT. See printout.	7/08	JP
EAST, Files PGPUB, USPAT, DERWENT. See printout.	7/08	JP
Reviewed the STN search done by STIC on 8/19/04 (full printout is in IFW)	7/08	JP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
424	404, 443, 486, 618, 619	7/08	JP
514	495	7/08	JP
EAST	PGPUB and USPAT text searched. See printout.	8/08	JP